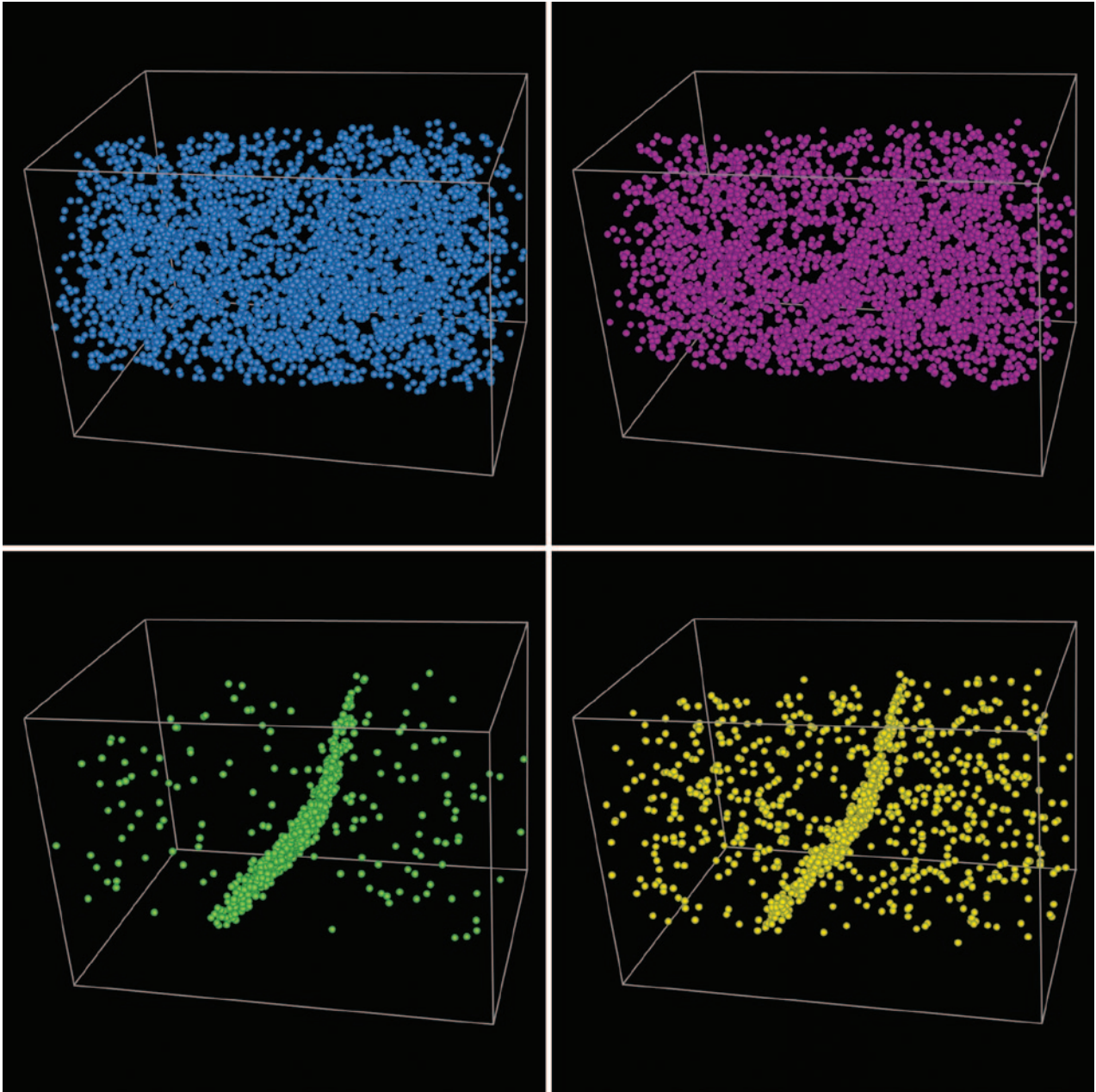


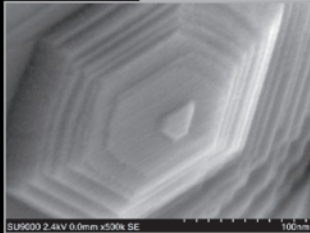
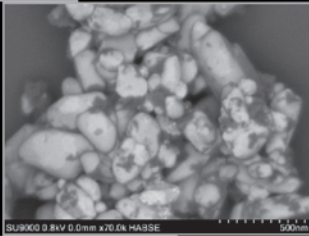
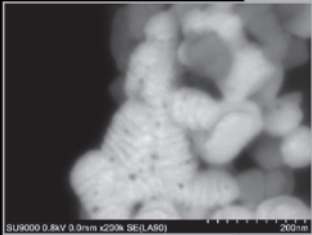
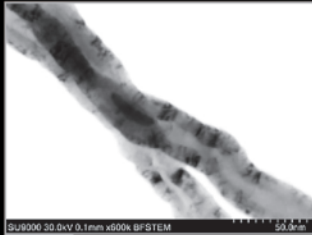
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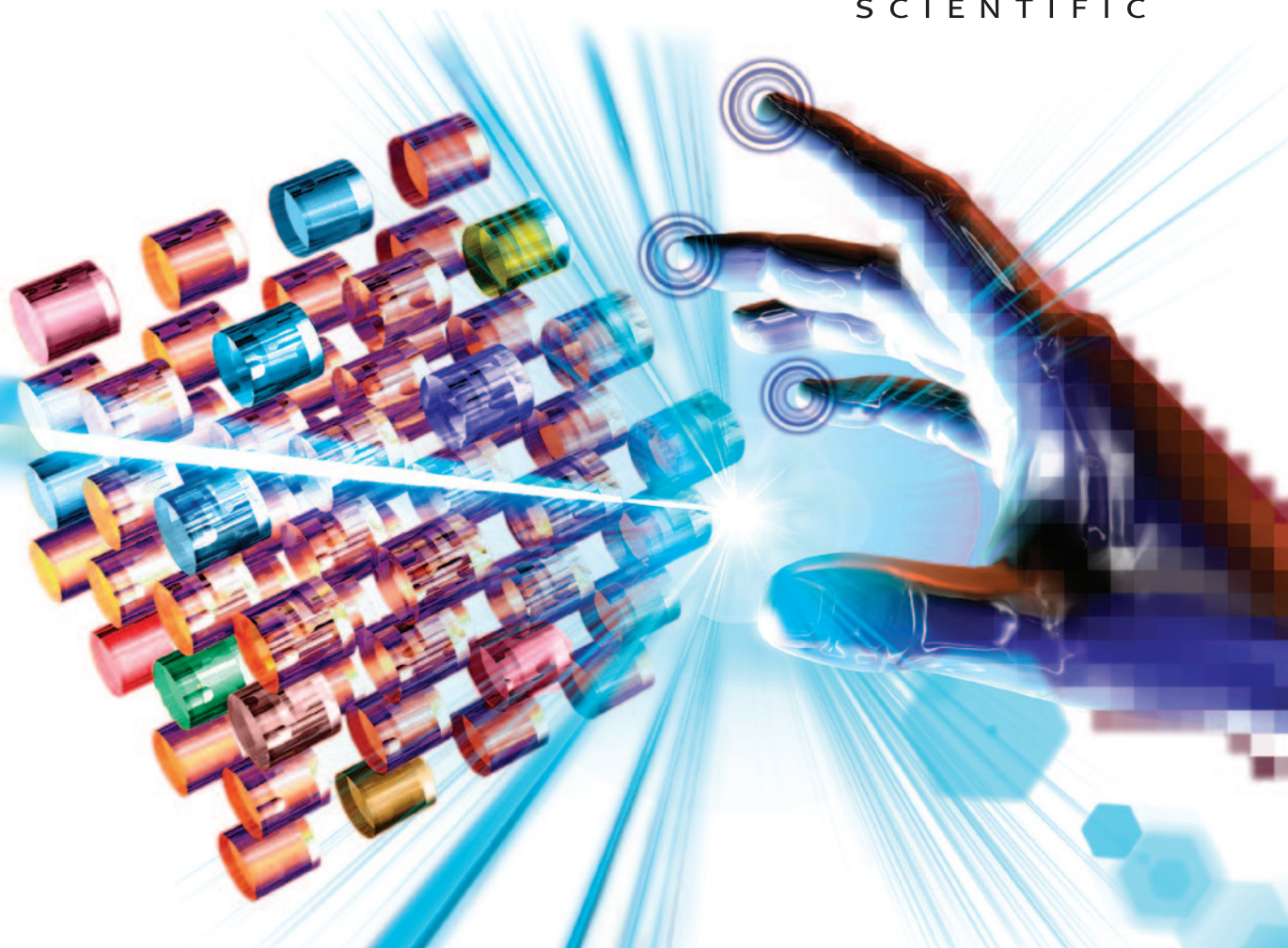
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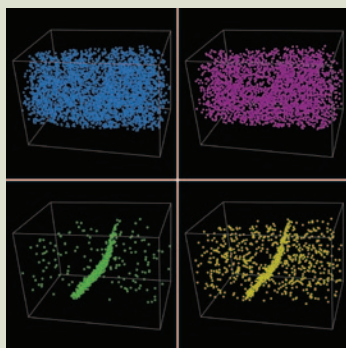
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### About the Cover



Atom probe 3D element maps of Cu(In,Ga)Se<sub>2</sub> solar cells showing Cu (blue) and In (magenta) matrix atoms and Na (green) and K (gold) impurity atoms. The size of the analyzed region is about 80 nm × 80 nm × 130 nm.

See article by Choi et al.





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